Application/Control No. O9/644,327 Reexamination UCHIYAMA, KENJI Examiner James A. Dudek Applicant(s)/Patent Under Reexamination UCHIYAMA, KENJI Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,323,930	11-2001	Higuchi et al.	349/152
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